

N-Channel Enhancement Mode MOSFET

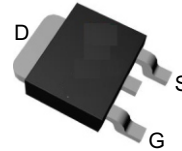
Features

- 40V/60A,
 $R_{DS(ON)} = 8m\Omega$ (Max.) @ $V_{GS} = 10V$
 $R_{DS(ON)} = 13m\Omega$ (Max.) @ $V_{GS} = 4.5V$
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

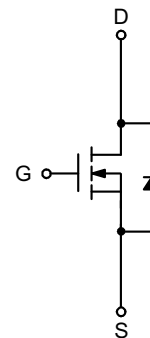
Applications

- Power Management in Desktop Computer or DC/DC Converters.

Pin Description



Top View of TO-252-3



N-Channel MOSFET

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Ratings ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)				
V_{DSS}	Drain-Source Voltage	40	V	
$BV_{DS(Avalanche)}^*$	Drain-Source Avalanche Voltage (Maximum)	45		
V_{GSS}	Gate-Source Voltage	± 20		
T_J	Maximum Junction Temperature	175	$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 175	$^\circ\text{C}$	
I_S	Diode Continuous Forward Current	40	A	
I_{DP}	300 μs Pulse Drain Current Tested	$T_C=25^\circ\text{C}$	160	A
		$T_C=100^\circ\text{C}$	90	
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	60***	A
		$T_C=100^\circ\text{C}$	48	
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	60	W
		$T_C=100^\circ\text{C}$	30	
R_{qJC}	Thermal Resistance-Junction to Case	2.5	$^\circ\text{C/W}$	
R_{qJA}	Thermal Resistance-Junction to Ambient	50	$^\circ\text{C/W}$	
E_{AS}^{**}	Drain-Source Avalanche Energy	L=0.5mH	100	mJ

Notes :

* Avalanche single pulse test and avalanche period time $t_{av} \leq 100 \mu\text{s}$, duty < 1% .

** Avalanche test condition: $T_J=25^\circ\text{C}$, L=0.5mH, $I_{AS}=20\text{A}$, $V_{DD}=30\text{V}$, and $V_{GS}=10\text{V}$.

*** Current limited by bond wire.

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	UTD60N04			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_{DS}=250\text{mA}$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=32\text{V}$, $V_{GS}=0\text{V}$	-	-	1	mA
		$T_J=85^\circ\text{C}$	-	-	30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=250\text{mA}$	1.5	2	3	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
$R_{DS(ON)}^a$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$, $I_{DS}=20\text{A}$	-	6.2	8	mW
		$V_{GS}=4.5\text{V}$, $I_{DS}=10\text{A}$	-	9.2	13	

Electrical Characteristics (Cont.) ($T_A = 25^\circ\text{C}$ unless otherwise noted)

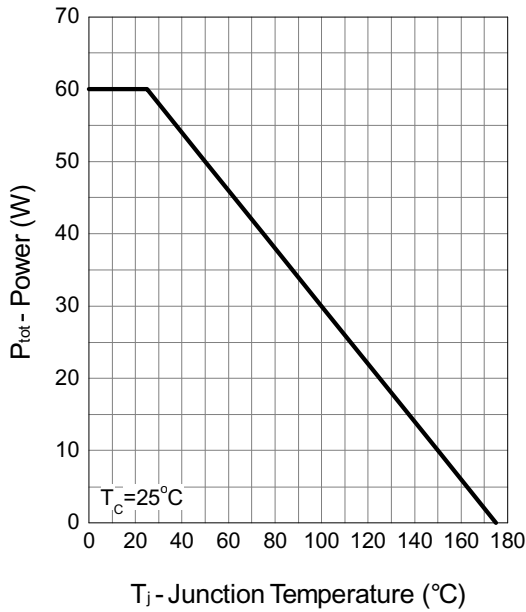
Symbol	Parameter	Test Conditions	UP60N04			Unit
			Min.	Typ.	Max.	
Diode Characteristics						
V_{SD}^a	Diode Forward Voltage	$I_{SD}=20\text{A}, V_{GS}=0\text{V}$	-	0.8	1.1	V
t_{rr}	Reverse Recovery Time	$I_{DS}=40\text{A}, di_{SD}/dt=100\text{A/ms}$	-	28	-	ns
Q_{rr}	Reverse Recovery Charge		-	24	-	nC
Dynamic Characteristics ^b						
R_G	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, F=1\text{MHz}$	-	1.4	-	W
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V},$ Frequency=1.0MHz	-	1460	-	pF
C_{oss}	Output Capacitance		-	180	-	
C_{riss}	Reverse Transfer Capacitance		-	146	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=20\text{V}, R_L=20\text{W},$ $I_{DS}=1\text{A}, V_{GEN}=10\text{V},$ $R_G=6\text{W}$	-	11	21	ns
t_r	Turn-on Rise Time		-	13	24	
$t_{d(OFF)}$	Turn-off Delay Time		-	37	67	
t_f	Turn-off Fall Time		-	11	21	
Gate Charge Characteristics ^b						
Q_g	Total Gate Charge	$V_{DS}=20\text{V}, V_{GS}=10\text{V},$ $I_{DS}=40\text{A}$	-	31.2	44	nC
Q_{gs}	Gate-Source Charge		-	3.8	-	
Q_{gd}	Gate-Drain Charge		-	9	-	

Note a : Pulse test ; pulse width?300ms, duty cycle?2%.

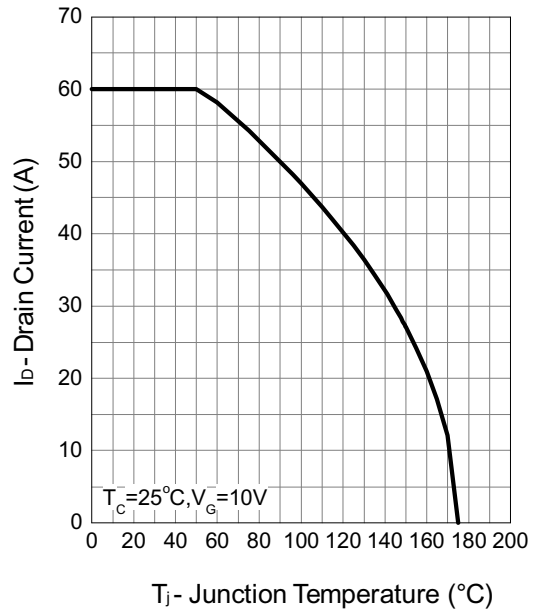
Note b : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

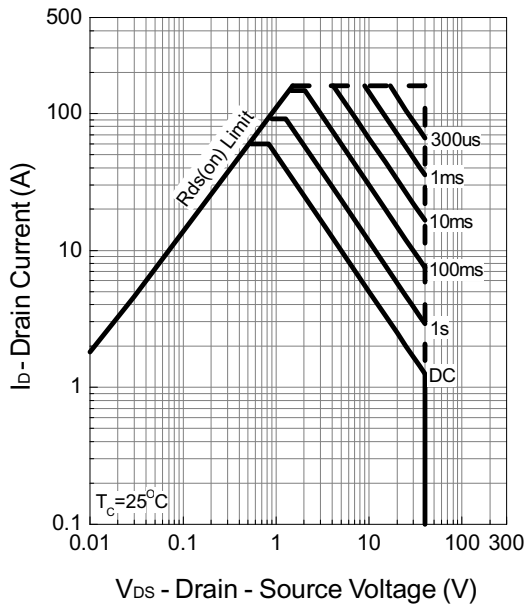
Power Dissipation



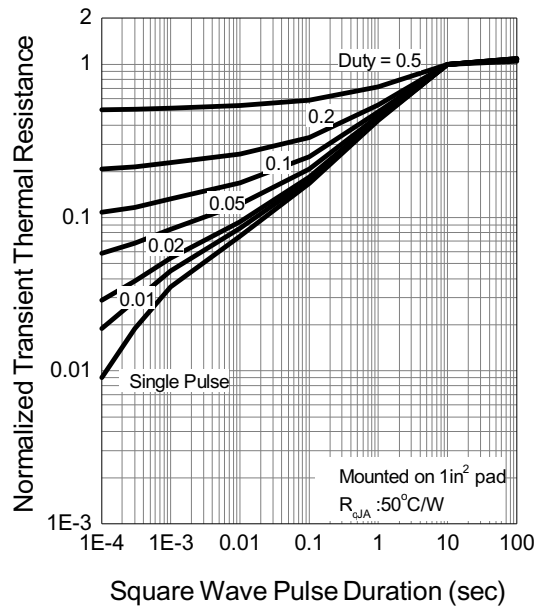
Drain Current



Safe Operation Area

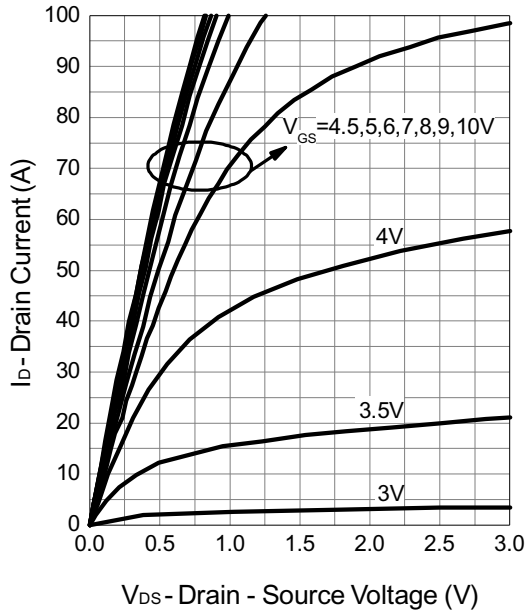


Thermal Transient Impedance

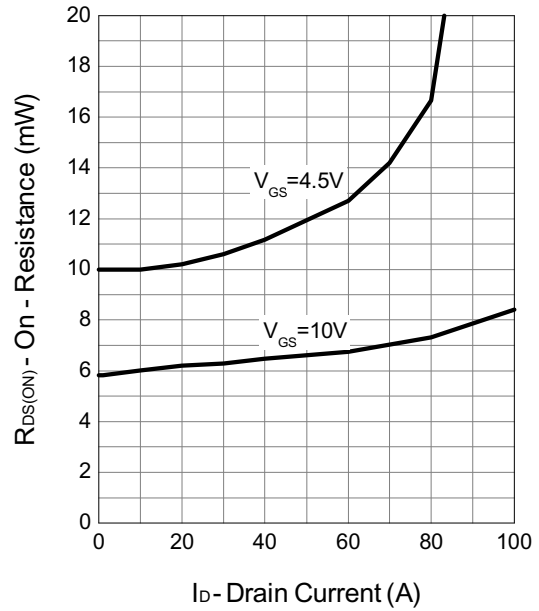


Typical Operating Characteristics (Cont.)

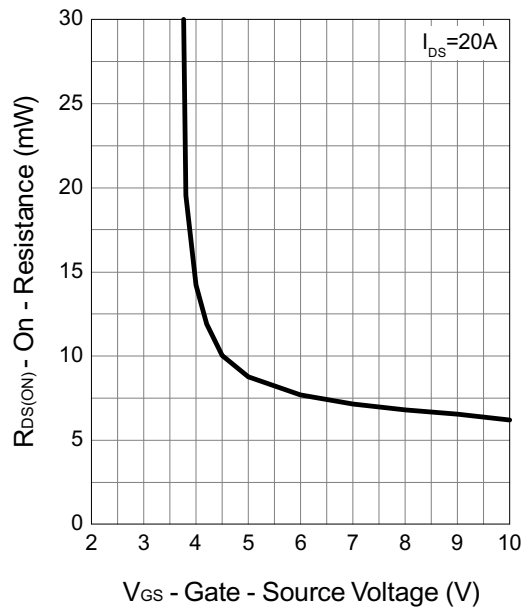
Output Characteristics



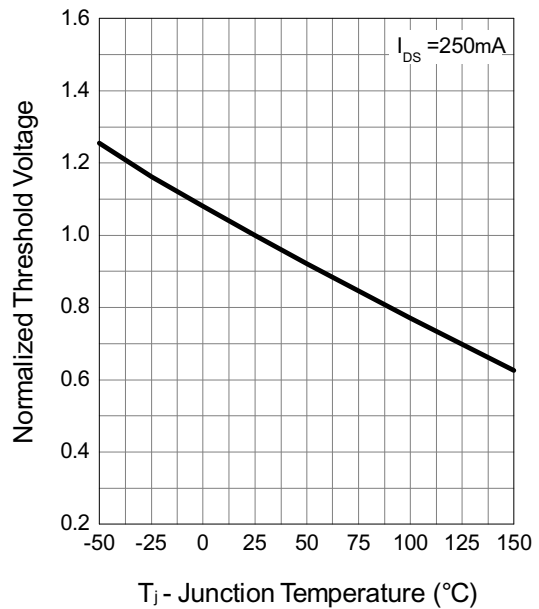
Drain-Source On Resistance



Gate-Source On Resistance

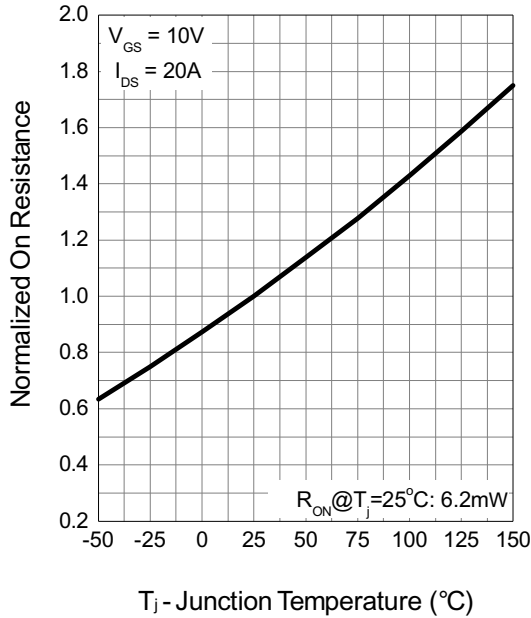


Gate Threshold Voltage

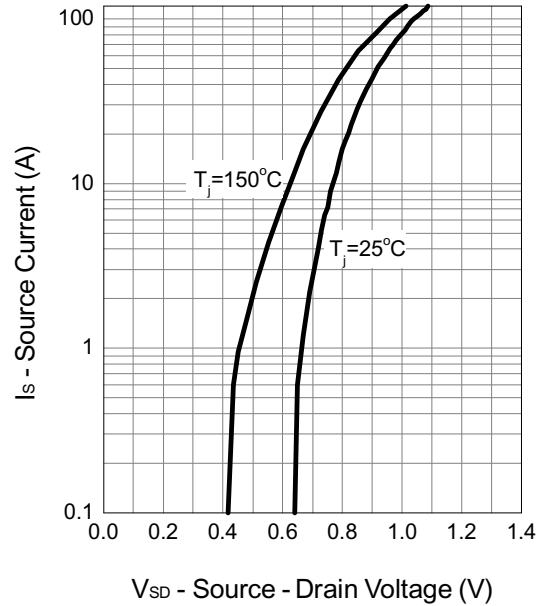


Typical Operating Characteristics (Cont.)

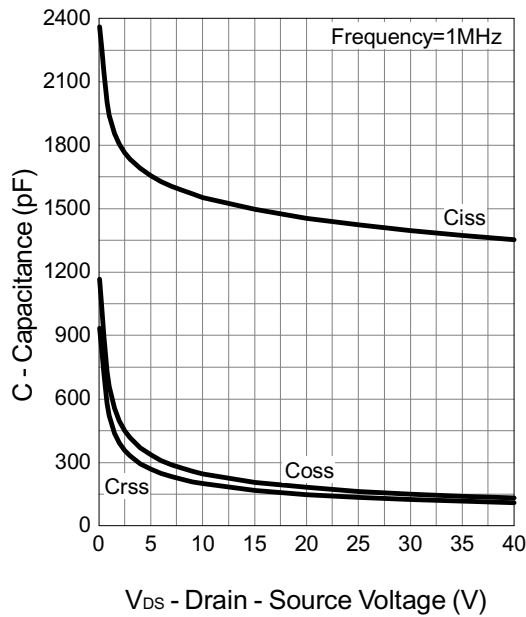
Drain-Source On Resistance



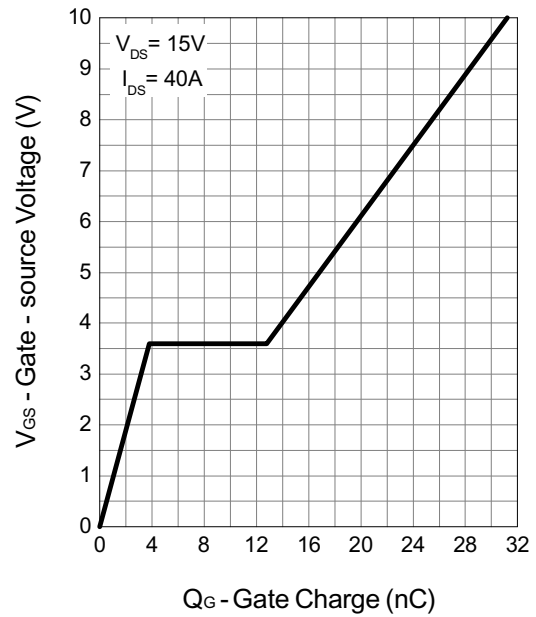
Source-Drain Diode Forward



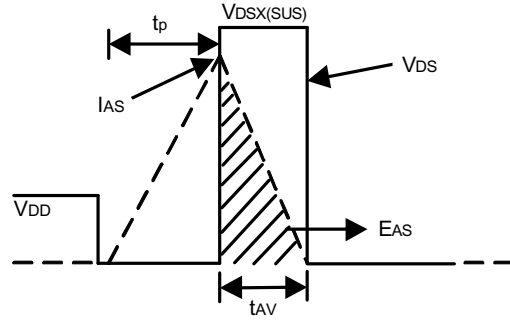
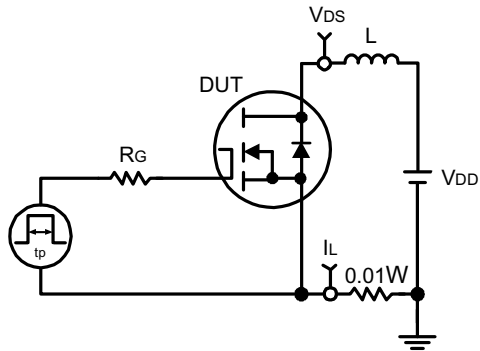
Capacitance



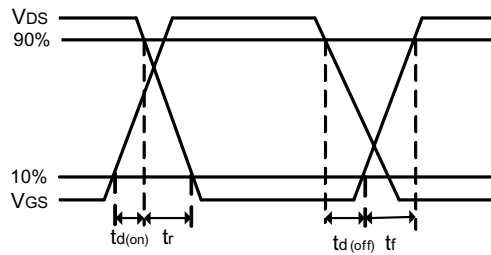
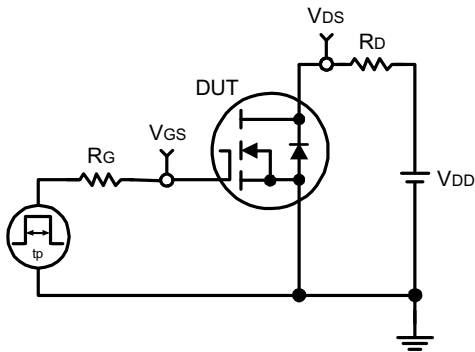
Gate Charge



Avalanche Test Circuit and Waveforms

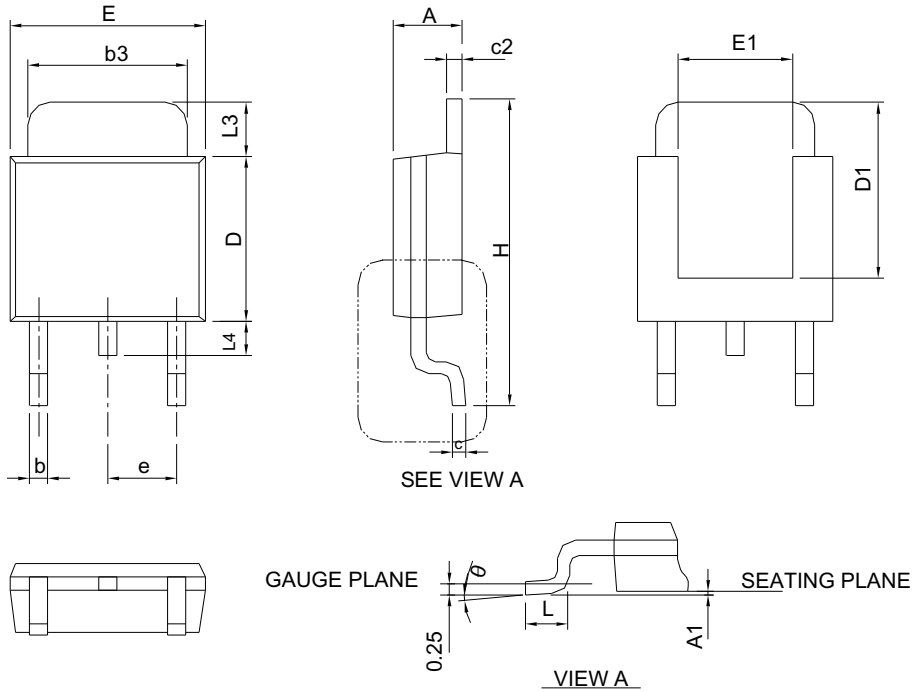


Switching Time Test Circuit and Waveforms



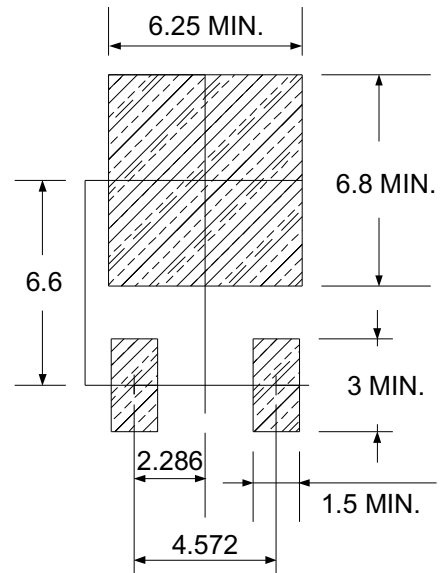
Package Information

TO-252-3



SYMBOL	TO-252-3			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	0.086	0.094
A1	-	0.13	-	0.005
b	0.50	0.89	0.020	0.035
b3	4.95	5.46	0.195	0.215
c	0.46	0.61	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.33	6.22	0.210	0.245
D1	4.57	6.00	0.180	0.236
E	6.35	6.73	0.250	0.265
E1	3.81	6.00	0.150	0.236
e	2.29 BSC		0.090 BSC	
H	9.40	10.41	0.370	0.410
L	0.90	1.78	0.035	0.070
L3	0.89	2.03	0.035	0.080
L4	-	1.02	-	0.040
θ	0°	8°	0°	8°

RECOMMENDED LAND PATTERN



UNIT: mm

Note : Follow JEDEC TO-252 .